

The TAOS II project

Preliminary results of a learning algorithm to
detect stellar occultations

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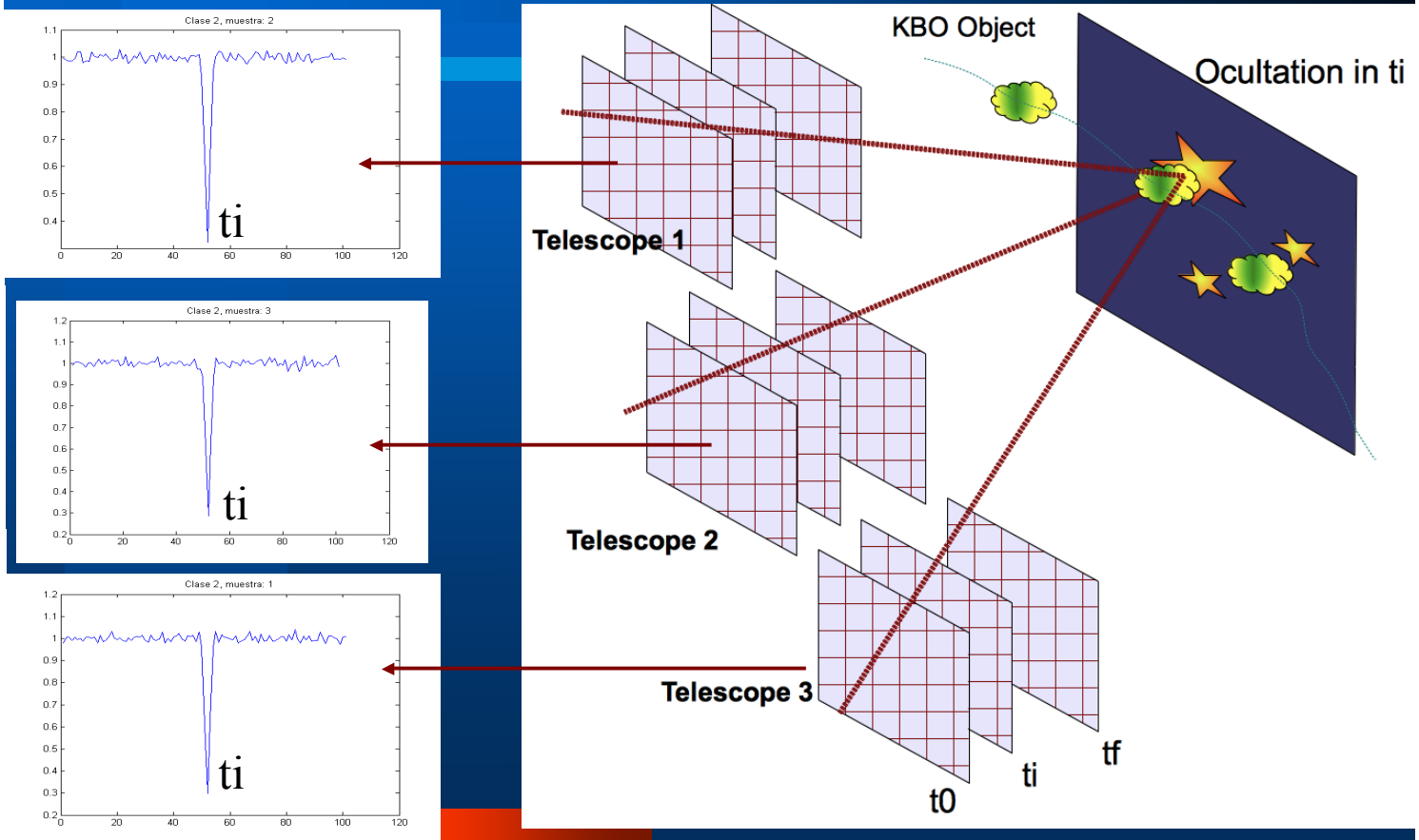
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Overview

- We use simulated diffraction patterns produced by the trans-Neptunian objects
- Our problem is to classify this type diffraction patterns.
- We extract three type of feature:
 - statistical,
 - differential operators
 - evolved interest point detector. Then,
- We use Support Vector Machine (SVM) approach as our classifier for occultation detections.
- For a set of 120 synthetic signals for the training process, 60 for the test stage, two classes of occultation and one with pure noise, our learning algorithm correctly detected 96% of the events.

Learning occultation algorithm



Learning occultation algorithm

Suppose that I have a set of the synthetic diffraction occultation pattern of an object in the Kuiper Belt.

$$\gamma_i(r, a, b_j, m, e, s)$$

r is the object diameter; a is the earth distance, b_j are different impact factors; m is the magnitude of the star; e is the spectral type of the star and s is the sample rate. Also we need to add some random noise such as

$$\Gamma_i = \gamma_i(r, a, b_j, m, e, s) \oplus \eta(\cdot)$$

Learning occultation algorithm

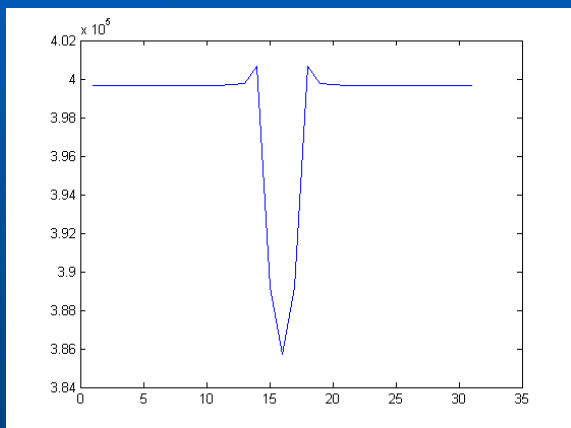
Then, our problem consists to finding a set of n independent features

$$\tau_k = f_k(\Gamma_1, \Gamma_2, \Gamma_3)$$

related with ***fk*** functions or relations, so that the set of n features $\{\tau_1, \tau_2, \dots, \tau_{k1}, \dots, \tau_n, y_m\}$ are associated to one class of occultation y_m

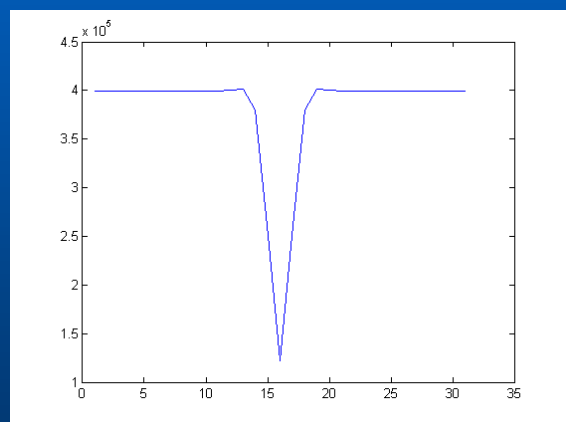
Learning occultation algorithm

We have 2 class of occultation and non occultation signal (a pure noise signal).



Label Class: 1
Diameter: 1 Km
Distance: 43 AU
Magnitude: 7
Transverse vel.: 25.425 km/s
LightCurve sampling: 10.0 Hz

$$\gamma_i(r, a, b_j, m, e, s)$$



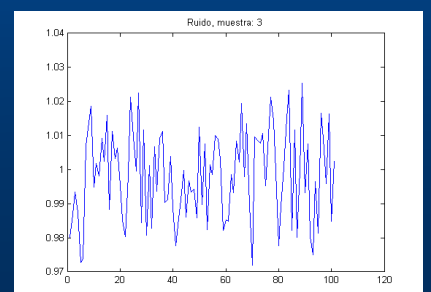
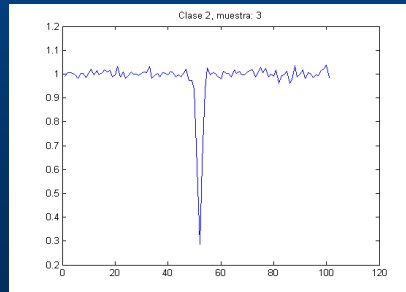
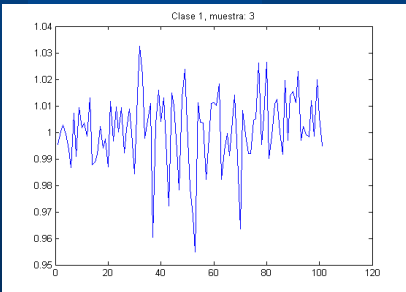
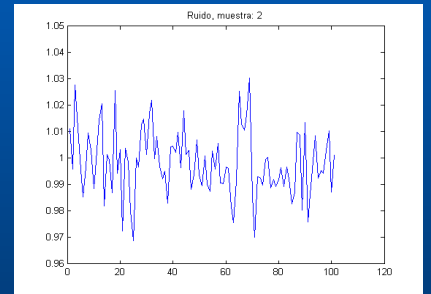
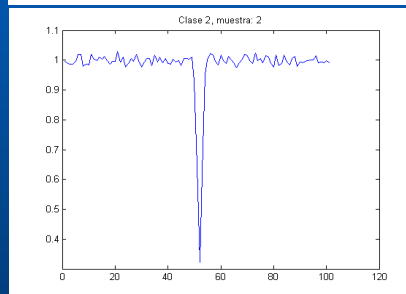
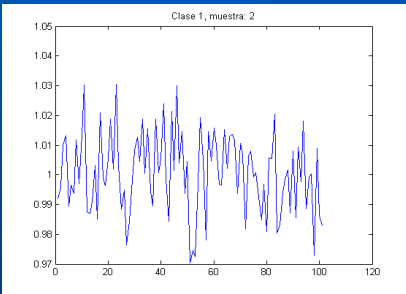
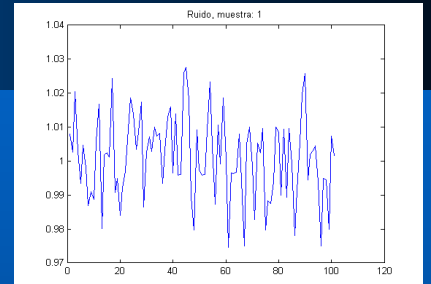
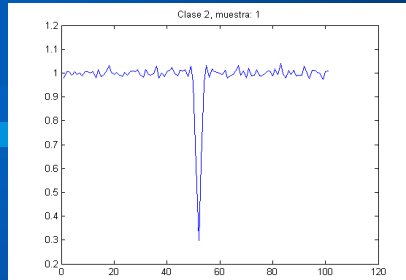
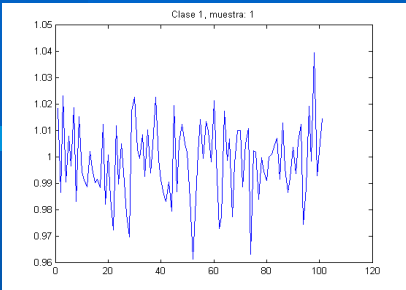
Label Class: 2
Diameter: 5 Km
Distance: 43 AU
Magnitude: 7
Transverse vel.: 25.425 km/s
LightCurve sampling: 10.0 Hz

$$\Gamma_i = \gamma_i(r, a, b_j, m, e, s) \oplus \eta(\cdot)$$

Class 1

Class 2

Class 3: non event



Features

We are include 3 type of features

- | Statistics
- | Differentials and Gaussian blur
- | Interest Point Operators according to Trujillo & Olague 2008

mean $\tau_1 = \frac{1}{T} \sum^T \Gamma_i$

variance $\tau_2 = \frac{1}{T-1} \sum^T (\Gamma_i - \bar{\Gamma})^2$

standard deviation $\tau_3 = \sqrt{\frac{1}{T-1} \sum^T (\Gamma_i - \bar{\Gamma})^2}$

$\tau_4 = \max_{imun}(\Gamma)$

In the next feature we are compute the operator using a kernel of 3 and 5 samples.

First derivative $\tau_{5,6} = \max\left(\frac{\partial\Gamma}{\partial t}\right)$

Second derivative $\tau_{7,8} = \max\left(\frac{\partial^2\Gamma}{\partial t^2}\right)$

Gaussian smooth operators.

$$\tau_{9,10} = \max(\Gamma * G_{\sigma=0.5})$$

$$\tau_{11,12} = \max(\Gamma * G_{\sigma=1})$$

$$\tau_{13,14} = \max(\Gamma * G_{\sigma=2})$$

$$\tau_{15,16} = \max(\Gamma * G_{\sigma=1} - \Gamma * G_{\sigma=0.5})$$

$$\tau_{17,18} = \max(\Gamma * G_{\sigma=2} - \Gamma * G_{\sigma=1})$$

$$\tau_{19,20} = \max((\Gamma * G_{\sigma=2} - \Gamma * G_{\sigma=1}) - (\Gamma * G_{\sigma=1} - \Gamma * G_{\sigma=0.5}))$$

The next feature are interest points detector. We employ a non maximum suppression schema (NMS) and count the numbers of interest point and its variance (var). We compute for a kernel of 3 and 5 pixels

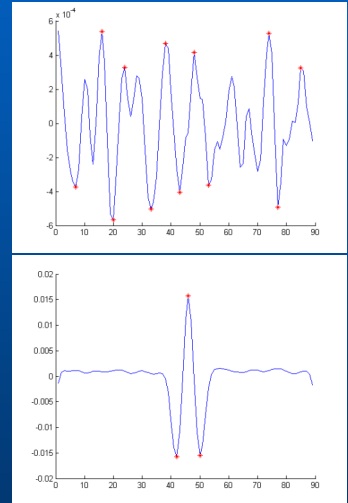
$$\tau_{21,22,23,24} = (NMS, \text{var}) \left(G_{\sigma=2} * (G_{\sigma=2} * \Gamma - \Gamma) \right)$$

$$\tau_{25,26,27,28} = (NMS, \text{var}) \left(G_{\sigma=2} * |\Gamma - G_{\sigma=2} * \Gamma|^2 \right)$$

$$\tau_{29,30,31,32} = (NMS, \text{var}) \left(G_{\sigma=1} * \left(\frac{G_{\sigma=1} * \Gamma}{(G_{\sigma=1} * G_{\sigma=1} * \Gamma)^3} \right) \right)$$

$$\tau_{33,34,35,36} = (NMS, \text{var}) \left(\frac{G_{\sigma=2} * \Gamma^{\frac{3}{2}}}{(G_{\sigma=1} * \Gamma)^{\frac{9}{4}}} \right)$$

$$\tau_{37,38,39,40} = (NMS, \text{var}) \left(G_{\sigma=2} * G_{\sigma=2} * [(G_{\sigma=2} * \Gamma)(G_{\sigma=2} * G_{\sigma=1} * \Gamma - \Gamma)] \right)$$



Results

- 3 Classes
- 40 signals in the training stage per class
- 20 signals per class for test

True\detected	1	2	3
1	20	0	0
2	0	20	0
3	1	0	19

Collaborators

- Students of the summer school of Astronomy.
 - Arturo Osorio
 - Ingeniería en Física. UAM Azcapotzalco
 - Miguel Angel Teran
 - Licenciatura en Física. UABC Ensenada

Some Author References

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Thank you!